

Notice of References Cited	Application/Control No. 10/562,767		Applicant(s)/Patent Under Reexamination HIROSHI, SHIMURA	
	Examiner Qing Chen		Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0124238 A1	09-2002	Metzgen, Paul	717/136
*	B	US-2002/0181765 A1	12-2002	Mori et al.	382/158
*	C	US-2003/0037321 A1	02-2003	Bowen, Matt	717/149
*	D	US-2003/0154466 A1	08-2003	Snider, Gregory S.	717/138
*	E	US-2004/0088685 A1	05-2004	Poznanovic et al.	717/140
*	F	US-2004/0261058 A1	12-2004	Kundert, Kenneth S.	717/119
*	G	US-6,226,776 B1	05-2001	Panchul et al.	716/3
*	H	US-6,625,797 B1	09-2003	Edwards et al.	716/18
*	I	US-6,631,391 B1	10-2003	Inabata et al.	708/495
*	J	US-6,983,456 B2	01-2006	Poznanovic et al.	717/133
*	K	US-6,988,192 B2	01-2006	Snider, Gregory S.	713/1
*	L	US-7,000,213 B2	02-2006	Banerjee et al.	716/18
*	M	US-7,039,233 B2	05-2006	Mori et al.	382/181

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Lee et al., "A Parallel and Accelerated Circuit Simulator with Precise Accuracy," 2002, IEEE.				
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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